Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/911,784	YOSHIYAMA ET AL.	
Examiner	Art Unit	
Khanh B. Pham	2166	

SEARCHED			
Class	Subclass	Date	Examiner
UPDATE	ALL	7/27/2006	KP
*			

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

STRATEGY	
DATE	EXMR
7/27/2006	KP
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